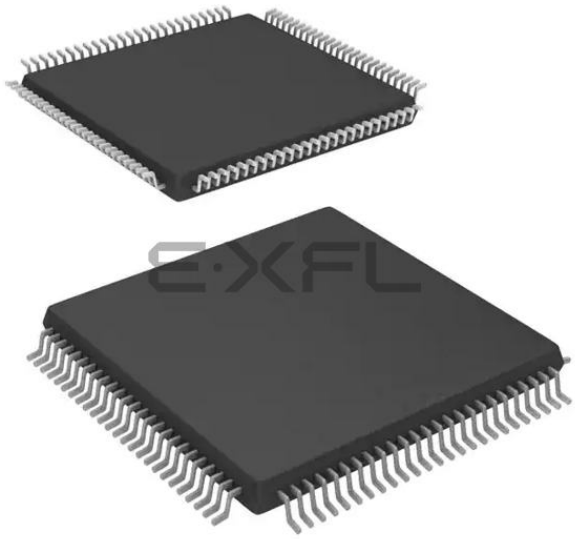


Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

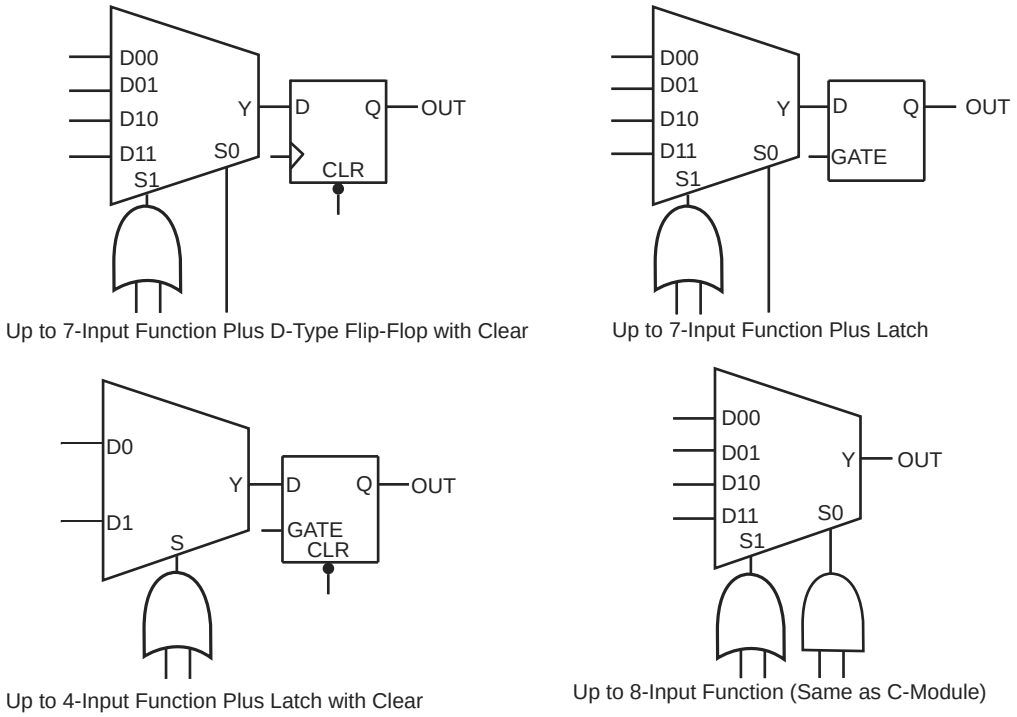
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-3vq100i

Table 1 • **Product profile**

Device	**A40MX02**	**A40MX04**	**A42MX09**	**A42MX16**	**A42MX24**	**A42MX36**
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	–	–	–	–	Yes	Yes
Boundary Scan Test (BST)	–	–	–	–	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	–
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	–	–
TQFP	–	–	176	176	176	–
CQFP	–	–	–	172	–	208, 256
PBGA	–	–	–	–	–	272
CPGA	–	–	132	–	–	–

Figure 4 • **42MX S-Module Implementation**



A42MX24 and A42MX36 devices contain D-modules, which are arranged around the periphery of the device. D-modules contain wide-decode circuitry, providing a fast, wide-input AND function similar to that found in CPLD architectures (Figure 5, page 9). The D-module allows A42MX24 and A42MX36 devices to perform wide-decode functions at speeds comparable to CPLDs and PALs. The output of the D-module has a programmable inverter for active HIGH or LOW assertion. The D-module output is hardwired to an output pin, and can also be fed back into the array to be incorporated into other logic.

3.2.2 Dual-Port SRAM Modules

The A42MX36 device contains dual-port SRAM modules that have been optimized for synchronous or asynchronous applications. The SRAM modules are arranged in 256-bit blocks that can be configured as 32x8 or 64x4. SRAM modules can be cascaded together to form memory spaces of user-definable width and depth. A block diagram of the A42MX36 dual-port SRAM block is shown in Figure 6, page 9.

The A42MX36 SRAM modules are true dual-port structures containing independent read and write ports. Each SRAM module contains six bits of read and write addressing (RDAD[5:0] and WRAD[5:0], respectively) for 64x4-bit blocks. When configured in byte mode, the highest order address bits (RDAD5 and WRAD5) are not used. The read and write ports of the SRAM block contain independent clocks (RCLK and WCLK) with programmable polarities offering active HIGH or LOW implementation. The SRAM block contains eight data inputs (WD[7:0]), and eight outputs (RD[7:0]), which are connected to segmented vertical routing tracks.

The A42MX36 dual-port SRAM blocks provide an optimal solution for high-speed buffered applications requiring FIFO and LIFO queues. The ACTgen Macro Builder within Microsemi's designer software provides capability to quickly design memory functions with the SRAM blocks. Unused SRAM blocks can be used to implement registers for other user logic within the design.

Figure 8 • **Clock Networks of 42MX Devices**

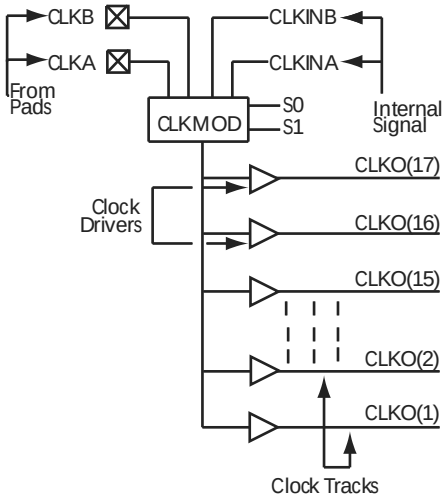
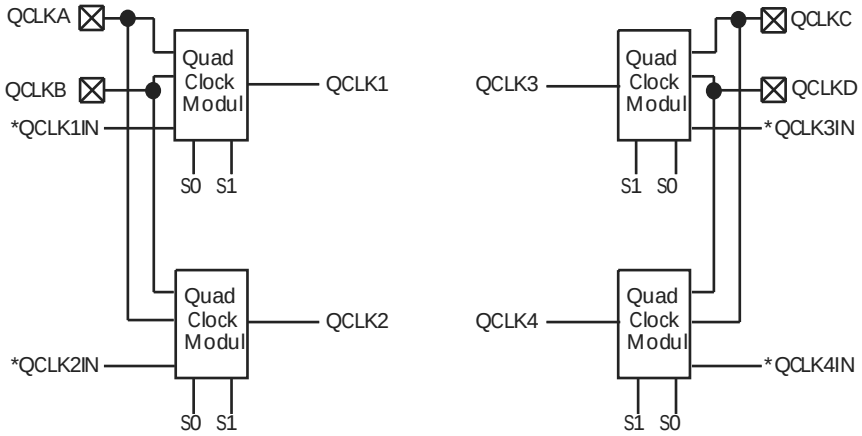


Figure 9 • **Quadrant Clock Network of A42MX36 Devices**



Note: *QCLK1IN, QCLK2IN, QCLK3IN, and QCLK4IN are internally-generated signals.

3.2.5 MultiPlex I/O Modules

42MX devices feature Multiplex I/Os and support 5.0 V, 3.3 V, and mixed 3.3 V/5.0 V operations.

The MultiPlex I/O modules provide the interface between the device pins and the logic array. Figure 10, page 12 is a block diagram of the 42MX I/O module. A variety of user functions, determined by a library macro selection, can be implemented in the module. (See the *Antifuse Macro Library Guide* for more information.) All 42MX I/O modules contain tristate buffers, with input and output latches that can be configured for input, output, or bidirectional operation.

All 42MX devices contain flexible I/O structures, where each output pin has a dedicated output-enable control (Figure 10, page 12). The I/O module can be used to latch input or output data, or both, providing fast set-up time. In addition, the Designer software tools can build a D-type flip-flop using a C-module combined with an I/O module to register input and output signals. See the *Antifuse Macro Library Guide* for more details.

A42MX24 and A42MX36 devices also offer selectable PCI output drives, enabling 100% compliance with version 2.1 of the PCI specification. For low-power systems, all inputs and outputs are turned off to reduce current consumption to below 500 µA.

To achieve 5.0 V or 3.3 V PCI-compliant output drives on A42MX24 and A42MX36 devices, a chip-wide PCI fuse is programmed via the Device Selection Wizard in the Designer software (Figure 11, page 12). When the PCI fuse is not programmed, the output drive is standard.

- VCCA = Power supply in volts (V)
- F = Switching frequency in megahertz (MHz)

3.4.4 Equivalent Capacitance

Equivalent capacitance is calculated by measuring ICCactive at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency-independent, so the results can be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

3.4.5 C_{EQ} Values for Microsemi MX FPGAs

Modules (C_{EQM})3.5

Input Buffers (C_{EQI})6.9

Output Buffers (C_{EQO})18.2

Routed Array Clock Buffer Loads (C_{EQCR})1.4

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. The equation below shows a piece-wise linear summation over all components.

$$\text{Power} = VCCA^2 * [(m \times C_{EQM} * f_m)_{modules} + (n * C_{EQI} * f_n)_{inputs} + (p * (C_{EQO} + C_L) * f_p)_{outputs} +$$
$$0.5 * (q_1 * C_{EQCR} * f_{q1})_{routed\_Clk1} + (r_1 * f_{q1})_{routed\_Clk1} +$$
$$0.5 * (q_2 * C_{EQCR} * f_{q2})_{routed\_Clk2} + (r_2 * f_{q2})_{routed\_Clk2} (2)]$$

EQ 3

where:

m = Number of logic modules switching at frequency f_m

n = Number of input buffers switching at frequency f_n

p = Number of output buffers switching at frequency f_p

q_1 = Number of clock loads on the first routed array clock

q_2 = Number of clock loads on the second routed array clock

r_1 = Fixed capacitance due to first routed array clock

r_2 = Fixed capacitance due to second routed array clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_L = Output load capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

3.4.9 JTAG Mode Activation

The JTAG test logic circuit is activated in the Designer software by selecting **Tools > Device Selection**. This brings up the Device Selection dialog box as shown in the following figure. The JTAG test logic circuit can be enabled by clicking the “Reserve JTAG Pins” check box. The following table explains the pins' behavior in either mode.

Figure 15 • **Device Selection Wizard**

Table 11 • **Boundary Scan Pin Configuration and Functionality**

Reserve JTAG	Checked	Unchecked
TCK	BST input; must be terminated to logical HIGH or LOW to avoid floating	User I/O
TDI, TMS	BST input; may float or be tied to HIGH	User I/O
TDO	BST output; may float or be connected to TDI of another device	User I/O

3.4.10 TRST Pin and TAP Controller Reset

An active reset (TRST) pin is not supported; however, MX devices contain power-on circuitry that resets the boundary scan circuitry upon power-up. Also, the TMS pin is equipped with an internal pull-up resistor. This allows the TAP controller to remain in or return to the Test-Logic-Reset state when there is no input or when a logical 1 is on the TMS pin. To reset the controller, TMS must be HIGH for at least five TCK cycles.

3.4.11 Boundary Scan Description Language (BSDL) File

Conforming to the IEEE Standard 1149.1 requires that the operation of the various JTAG components be documented. The BSDL file provides the standard format to describe the JTAG components that can be used by automatic test equipment software. The file includes the instructions that are supported, instruction bit pattern, and the boundary-scan chain order. For an in-depth discussion on BSDL files, see the *BSDL Files Format Description* application note.

BSDL files are grouped into two categories - generic and device-specific. The generic files assign all user I/Os as inouts. Device-specific files assign user I/Os as inputs, outputs or inouts.

Generic files for MX devices are available on the Microsemi SoC Product Group's website:

http://www.microsemi.com/soc/techdocs/models/bsdl.html.

3.5 Development Tool Support

The MX family of FPGAs is fully supported by Libero® Integrated Design Environment (IDE). Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes SynplifyPro from Synopsys, ModelSim® HDL Simulator from Mentor Graphics® and Viewdraw.

Libero IDE includes place-and-route and provides a comprehensive suite of backend support tools for FPGA development, including timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor.

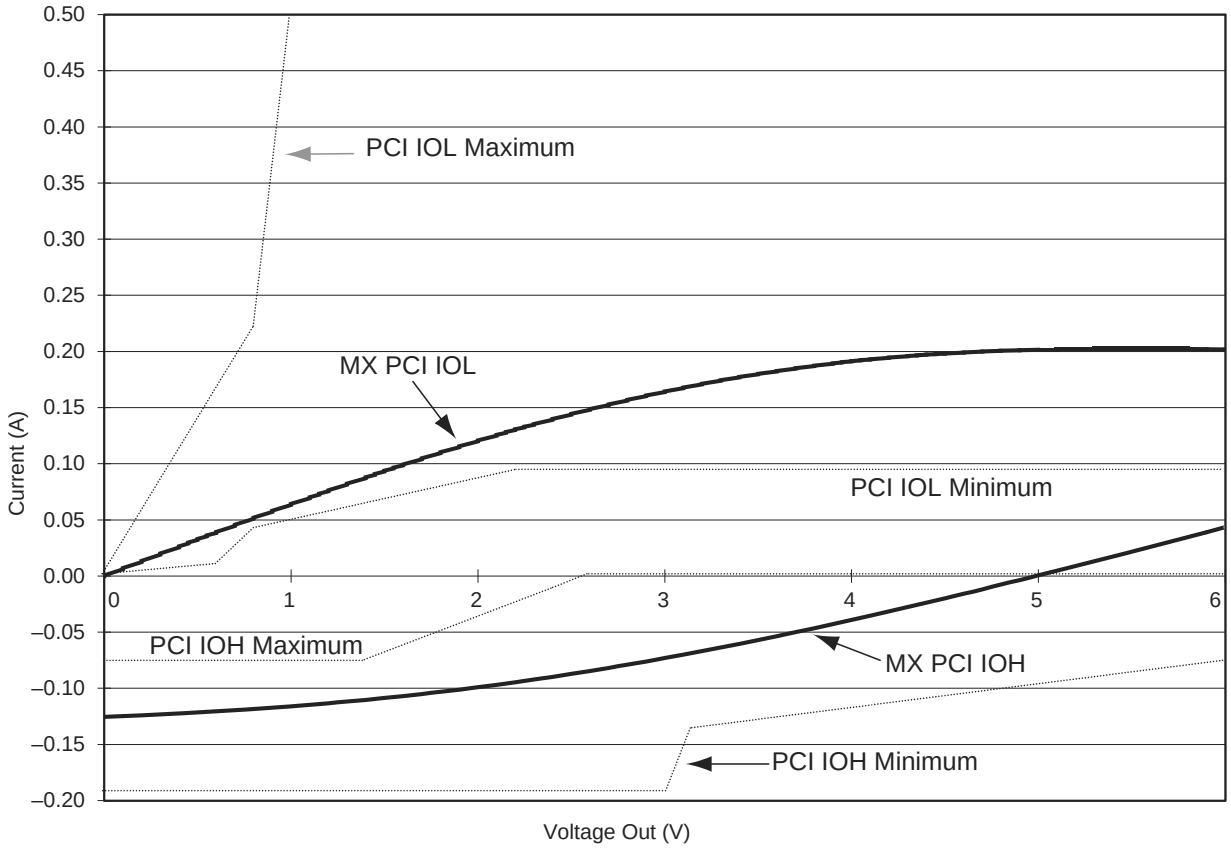
reliability. Devices should not be operated outside the recommended operating conditions.

Table 21 • **Recommended Operating Conditions**

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCCA	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI	3.14 to 3.47	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

Figure 16 • **Typical Output Drive Characteristics (Based Upon Measured Data)**



3.9.4 Junction Temperature (T_J)

The temperature variable in the Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because the heat generated from dynamic power consumption is usually hotter than the ambient temperature. The following equation can be used to calculate junction temperature.

$$\text{Junction Temperature} = \Delta T + T_a \quad (1)$$

EQ 4

where:

- T_a = Ambient Temperature
- ΔT = Temperature gradient between junction (silicon) and ambient
- $\Delta T = \theta_{ja} * P$ (2)
- P = Power
- θ_{ja} = Junction to ambient of package. θ_{ja} numbers are located in Table 27, page 29.

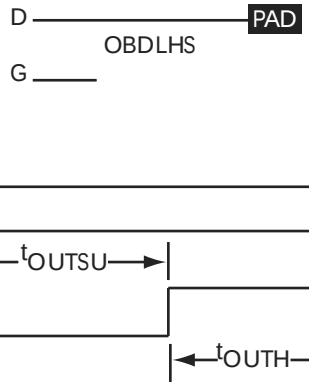
3.9.5 Package Thermal Characteristics

The device junction-to-case thermal characteristic is θ_{jc}, and the junction-to-ambient air characteristic is θ_{ja}. The thermal characteristics for θ_{ja} are shown with two different air flow rates.

The maximum junction temperature is 150°C.

Maximum power dissipation for commercial- and industrial-grade devices is a function of θ_{ja}.

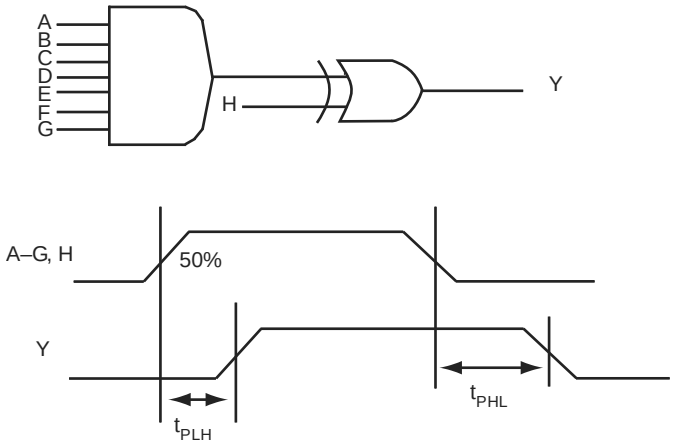
Figure 27 • **Output Buffer Latches**



3.10.4 Decode Module Timing

The following figure shows decode module timing.

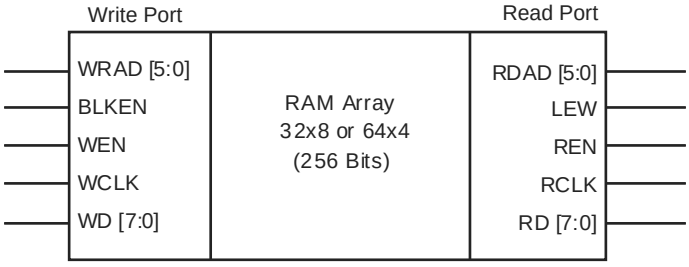
Figure 28 • **Decode Module Timing**



3.10.5 SRAM Timing Characteristics

The following figure shows SRAM timing characteristics.

Figure 29 • **SRAM Timing Characteristics**



3.10.6 Dual-Port SRAM Timing Waveforms

The following figures show dual-port SRAM timing waveforms.

Table 36 • **A40MX04 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing[1]												
t_{DLH}	Data-to-Pad HIGH		3.9		4.5		5.1		6.05		8.5	ns
t_{DHL}	Data-to-Pad LOW		3.4		3.9		4.4		5.2		7.3	ns
t_{ENZH}	Enable Pad Z to HIGH		3.4		3.9		4.4		5.2		7.3	ns
t_{ENZL}	Enable Pad Z to LOW		4.9		5.6		6.4		7.5		10.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.0	ns
t_{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d_{TLH}	Delta LOW to HIGH		0.03		0.04		0.04		0.05		0.07	ns/pF
d_{THL}	Delta HIGH to LOW		0.02		0.02		0.03		0.03		0.04	ns/pF

1. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer utility from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading

Table 37 • **A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.7		2.0		2.3		2.7		3.7	ns
t_{PD2}	Dual-Module Macros		3.7		4.3		4.9		5.7		8.0	ns
t_{CO}	Sequential Clock-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{GO}	Latch G-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.7		2.0		2.3		2.7		3.7	ns
Logic Module Predicted Routing Delays[1]												
t_{RD1}	FO = 1 Routing Delay		1.9		2.2		2.5		3.0		4.2	ns
t_{RD2}	FO = 2 Routing Delay		2.7		3.1		3.5		4.1		5.7	ns
t_{RD3}	FO = 3 Routing Delay		3.4		3.9		4.4		5.2		7.3	ns
t_{RD4}	FO = 4 Routing Delay		4.1		4.8		5.4		6.3		8.9	ns
t_{RD8}	FO = 8 Routing Delay		7.1		8.1		9.2		10.9		15.2	ns
Logic Module Sequential Timing[2]												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	4.3		5.0		5.6		6.6		9.2		ns
t_{HD}[3]	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	4.3		5.0		5.6		6.6		9.2		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns

Table 39 • **A42MX09 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t_{DHL}	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t_{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t_{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t_{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. *For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*
3. *Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.*
4. *Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.*
5. *Delays based on 35 pF loading.*

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.4		1.5		1.7		2.0		2.8	ns
t_{CO}	Sequential Clock-to-Q		1.4		1.6		1.8		2.1		3.0	ns
t_{GO}	Latch G-to-Q		1.4		1.5		1.7		2.0		2.8	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.6		1.7		2.0		2.3		3.3	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.6	ns
t_{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1	ns

Table 45 • **A42MX36 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			2.8		3.1		3.5		4.1		5.7	ns
t_{IRD2}	FO = 2 Routing Delay			3.2		3.5		4.1		4.8		6.7	ns
t_{IRD3}	FO = 3 Routing Delay			3.7		4.1		4.7		5.5		7.7	ns
t_{IRD4}	FO = 4 Routing Delay			4.2		4.6		5.3		6.2		8.7	ns
t_{IRD8}	FO = 8 Routing Delay			6.1		6.8		7.7		9.0		12.6	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32		4.6		5.1		5.7		6.7		9.3	ns
		FO = 635		5.0		5.6		6.3		7.4		10.3	ns
t_{CKL}	Input HIGH to LOW	FO = 32		5.3		5.9		6.7		7.8		11.0	ns
		FO = 635		6.8		7.6		8.6		10.1		14.1	ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t_{PWL}	Minimum Pulse Width LOW	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t_{CKSW}	Maximum Skew	FO = 32		1.0		1.2		1.3		1.5		2.2	ns
		FO = 635		1.0		1.2		1.3		1.5		2.2	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 635	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	4.0		4.4		5.0		5.9		8.2		ns
		FO = 635	4.6		5.2		5.9		6.9		9.6		ns
t_P	Minimum Period ($1/f_{MAX}$)	FO = 32	9.2		10.2		11.1		12.7		21.2		ns
		FO = 635	9.9		11.0		12.0		13.8		23.0		ns
f_{MAX}	Maximum Datapath Frequency	FO = 32		108		98		90		79		47	MHz
		FO = 635		100		91		83		73		44	MHz
TTL Output Module Timing[5]													
t_{DLH}	Data-to-Pad HIGH			3.6		4.0		4.5		5.3		7.4	ns
t_{DHL}	Data-to-Pad LOW			4.2		4.6		5.2		6.2		8.6	ns
t_{ENZH}	Enable Pad Z to HIGH			3.7		4.2		4.7		5.5		7.7	ns
t_{ENZL}	Enable Pad Z to LOW			4.1		4.6		5.2		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z			7.34		8.2		9.3		10.9		15.3	ns
TTL Output Module Timing[5]													
t_{ENLZ}	Enable Pad LOW to Z			6.9		7.6		8.7		10.2		14.3	ns
t_{GLH}	G-to-Pad HIGH			4.9		5.5		6.2		7.3		10.2	ns
t_{GHL}	G-to-Pad LOW			4.9		5.5		6.2		7.3		10.2	ns
t_{LSU}	I/O Latch Output Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.9		8.8		10.0		11.8		16.5	ns

Table 48 • **PL68**

PL68		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
24	I/O	I/O
25	VCC	VCC
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	I/O	I/O
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	VCC	VCC
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	GND	GND
50	I/O	I/O
51	I/O	I/O
52	CLK, I/O	CLK, I/O
53	I/O	I/O
54	MODE	MODE
55	VCC	VCC
56	SDI, I/O	SDI, I/O
57	DCLK, I/O	DCLK, I/O
58	PRA, I/O	PRA, I/O
59	PRB, I/O	PRB, I/O
60	I/O	I/O

Table 50 • **PQ 100**

PQ100				
Pin Number	**A40MX02 Function**	**A40MX04 Function**	**A42MX09 Function**	**A42MX16 Function**
56	VCC	VCC	I/O	I/O
57	I/O	I/O	GND	GND
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	I/O	I/O	I/O	I/O
61	I/O	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	GND	GND	I/O	I/O
64	I/O	I/O	LP	LP
65	I/O	I/O	VCCA	VCCA
66	I/O	I/O	VCCI	VCCI
67	I/O	I/O	VCCA	VCCA
68	I/O	I/O	I/O	I/O
69	VCC	VCC	I/O	I/O
70	I/O	I/O	I/O	I/O
71	I/O	I/O	I/O	I/O
72	I/O	I/O	GND	GND
73	I/O	I/O	I/O	I/O
74	I/O	I/O	I/O	I/O
75	I/O	I/O	I/O	I/O
76	I/O	I/O	I/O	I/O
77	NC	NC	I/O	I/O
78	NC	NC	I/O	I/O
79	NC	NC	SDI, I/O	SDI, I/O
80	NC	I/O	I/O	I/O
81	NC	I/O	I/O	I/O
82	NC	I/O	I/O	I/O
83	I/O	I/O	I/O	I/O
84	I/O	I/O	GND	GND
85	I/O	I/O	I/O	I/O
86	GND	GND	I/O	I/O
87	GND	GND	PRA, I/O	PRA, I/O
88	I/O	I/O	I/O	I/O
89	I/O	I/O	CLKA, I/O	CLKA, I/O
90	CLK, I/O	CLK, I/O	VCCA	VCCA
91	I/O	I/O	I/O	I/O
92	MODE	MODE	CLKB, I/O	CLKB, I/O

Figure 42 • **PQ144**

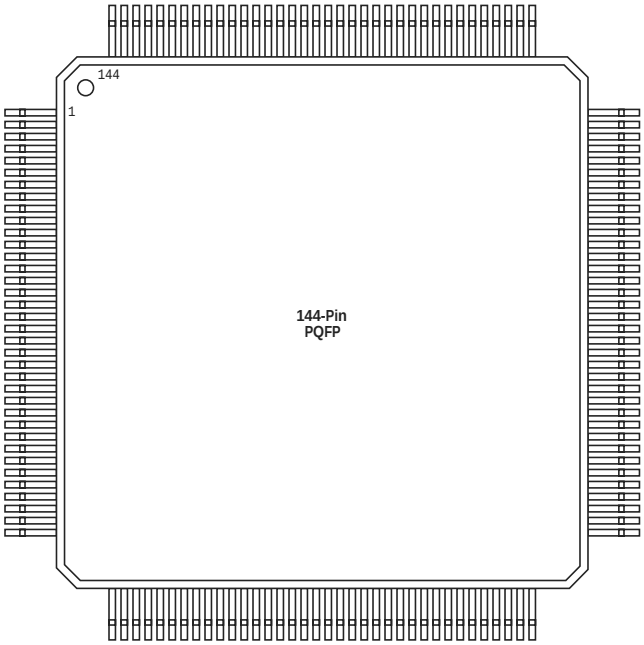


Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
117	GNDI
118	NC
119	I/O
120	I/O
121	I/O
122	I/O
123	PROBA
124	I/O
125	CLKA
126	VCC
127	VCCI
128	NC
129	I/O
130	CLKB
131	I/O
132	PROBB
133	I/O
134	I/O
135	I/O
136	GND
137	GNDI
138	NC
139	I/O
140	I/O
141	I/O
142	I/O
143	I/O
144	DCLK

Table 53 • **PQ208**

PQ208			
Pin Number	**A42MX16 Function**	**A42MX24 Function**	**A42MX36 Function**
95	NC	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	VCCI	VCCI	VCCI
99	I/O	I/O	I/O
100	I/O	WD, I/O	WD, I/O
101	I/O	WD, I/O	WD, I/O
102	I/O	I/O	I/O
103	SDO, I/O	SDO, TDO, I/O	SDO, TDO, I/O
104	I/O	I/O	I/O
105	GND	GND	GND
106	NC	VCCA	VCCA
107	I/O	I/O	I/O
108	I/O	I/O	I/O
109	I/O	I/O	I/O
110	I/O	I/O	I/O
111	I/O	I/O	I/O
112	NC	I/O	I/O
113	NC	I/O	I/O
114	NC	I/O	I/O
115	NC	I/O	I/O
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	I/O	I/O	I/O
126	GND	GND	GND
127	I/O	I/O	I/O
128	I/O	TCK, I/O	TCK, I/O
129	LP	LP	LP
130	VCCA	VCCA	VCCA
131	GND	GND	GND

Table 60 • **BG272**

BG272	
Pin Number	**A42MX36 Function**
D20	I/O
E1	I/O
E2	I/O
E3	I/O
E4	VCCA
E17	VCCI
E18	I/O
E19	I/O
E20	I/O
F1	I/O
F2	I/O
F3	I/O
F4	VCCI
F17	I/O
F18	I/O
F19	I/O
F20	I/O
G1	I/O
G2	I/O
G3	I/O
G4	VCCI
G17	VCCI
G18	I/O
G19	I/O
G20	I/O
H1	I/O
H2	I/O
H3	I/O
H4	VCCA
H17	I/O
H18	I/O
H19	I/O
H20	I/O
J1	I/O
J2	I/O
J3	I/O
J4	VCCI

Table 60 • **BG272**

BG272	
Pin Number	**A42MX36 Function**
V16	I/O
V17	I/O
V18	SDO, TDO, I/O
V19	I/O
V20	I/O
W1	GND
W2	GND
W3	I/O
W4	TMS, I/O
W5	I/O
W6	I/O
W7	I/O
W8	WD, I/O
W9	WD, I/O
W10	I/O
W11	I/O
W12	I/O
W13	WD, I/O
W14	I/O
W15	I/O
W16	WD, I/O
W17	I/O
W18	WD, I/O
W19	GND
W20	GND
Y1	GND
Y2	GND
Y3	I/O
Y4	TDI, I/O
Y5	WD, I/O
Y6	I/O
Y7	QCLKA, I/O
Y8	I/O
Y9	I/O
Y10	I/O
Y11	I/O
Y12	I/O

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
G12	VSV
F13	I/O
F12	I/O
F11	I/O
F10	I/O
E13	I/O
D13	I/O
D12	I/O
C13	I/O
B13	I/O
D11	I/O
C12	I/O
A13	I/O
C11	I/O
B12	SDI
B11	I/O
C10	I/O
A12	I/O
A11	I/O
B10	I/O
D8	I/O
A10	I/O
C8	I/O
A9	I/O
B8	PRBA
A8	I/O
B7	CLKA
A7	I/O
B6	CLKB
A6	I/O
C6	PRBB
A5	I/O
D6	I/O
A4	I/O
B4	I/O
A3	I/O
C4	I/O